# Application/Control No. 10/080,823 Examiner Phallaka Kik Applicant(s)/Patent Under Reexamination HINO ET AL. Art Unit 2825 Page 1 of 1

# Notice of References Cited

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,754,171	05-1998	Stoller, Ray A.	345/205
	В	US-6,550,047	04-2003	Becker, Scott T.	716/8
	C.	US-5,699,073	12-1997	Lebby et al.	345/82
	D	US-5,680,191	10-1997	Voisin et al.	349/150
	Е	US-			
	F	ÙS-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

### **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
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	R					
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	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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